





NFC TEST REPORT

No.120Z70323-IOT01

for

Samsung Electronics Co.,Ltd

Smart Phone

SM-A025G/DSN

FCC ID: ZCASMA025G

with

Hardware Version: REV1.0

Software Version: A025G.001

Issued Date: 2020-12-01

Note:

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of CTTL.

The report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the U.S.Government.

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REPORT HISTORY

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1. Test Laboratory

1.1. Introduction & Accreditation

Telecommunication Technology Labs, CAICT is an ISO/IEC 17025:2005 accredited test laboratory under NATIONAL VOLUNTARY LABORATORY ACCREDITATION PROGRAM (NVLAP) with lab code 600118-0, and is also an FCC accredited test laboratory (CN5017), and ISED accredited test laboratory (ISED#: 24849). The detail accreditation scope can be found on NVLAP website.

1.2. <u>Testing Location</u>

Location 1: CTTL(huayuan North Road)

Address: No. 52, Huayuan North Road, Haidian District, Beijing,

P. R. China 100191

Location 2: CTTL(BDA)

Address: No.18A, Kangding Street, Beijing Economic-Technology

Development Area, Beijing, P. R. China 100176





1.3. <u>Testing Environment</u>

Normal Temperature: 15-35°C

Extreme Temperature: -20/+50°C

Normal Relative Humidity: 20-75%

Normal Air Pressure 86Kpa-106Kpa

1.4. Project data

Testing Start Date: 2020-11-09

Testing End Date: 2020-11-10

1.5. Signature

Zhou Bin

(Prepared this test report)

Pang Shuai

(Reviewed this test report)

Zhu Liang

(Approved this test report)





2. Client Information

2.1. Applicant Information

Company Name: Samsung Electronics Co,. Ltd.

Address: 19 Chapin Rd., Building D Pine Brook, NJ07058

Country: America

Contact: Jenni Chun

Telephone: +1-201-937-4203

E-mail: j1.chun@samsung.com

2.2. Manufacturer Information

Company Name: Samsung Electronics Co,. Ltd.

Samsung R5,Maetan dong 129,Samsung ro Youngtong gu,Suwon Address:

city 443 742,Korea

Country: Korea

Contact: Sunghoon Cho

Telephone: +82-10-2722-4159

E-mail: ggobi.cho@samsung.com





3. Equipment Under Test (EUT) and Ancillary Equipment (AE)

3.1. About EUT

Description Smart Phone

Model name/HVIN SM-A025G/DSN

Brand name SAMSUNG

FCC ID ZCASMA025G

UMTS Frequency Band(s) FDD I/V/VIII

GSM Frequency Band(s) GSM1900/850/900/1800

E-UTRA Frequency Band(s) FDD 1/3/5/7/8/20/28/28a/28b TDD 38/40/41

Extreme Temperature -10/+55°C

Nominal Voltage 3.85V

Extreme High Voltage 4.2V

Extreme Low Voltage 3.6V

3.2. <u>Internal Identification of EUT</u>

EUT ID*	IMEI/SNI	HW Version	SW Version	Date of receipt
08a	207032308a	REV1.0	A025G.001	2020-11-03
01a	207032301a	REV1.0	A025G.001	2020-10-28

^{*}EUT ID: is used to identify the test sample in the lab internally.

3.3. Internal Identification of AE

Manufacturer

AE ID*	Description	SN
AE1	Charger1	1
AE2	Charger2	1
AE3	Charger3	1
AE4	Charger4	1
AE5	Charger5	1
AE6	USB cable	1
AE7	Headset1	1
AE8	Headset2	1
AE9	battery	1
AE1		
Model	EP-TA50JWE	

HAEM Co.,Ltd





Length of cable /

AE2

Model EP-TA50JWE

Manufacturer RFTech Electronics(HuiZhou)Co.,LTD

Length of cable

AE3

Model EP-TA200 Manufacturer HAEM Co.,Ltd

Length of cable

AE4

Model EP-TA200

Manufacturer RFTech Electronics(HuiZhou)Co.,LTD

Length of cable /

AE5

Model EP-TA200 Manufacturer SoluM Co.,Ltd

Length of cable

AE6

Model EP-DR140AWE

Manufacturer Samsung Electronics Co., Ltd.

Length of cable

AE7

Model EHS61ASFWE

Manufacturer DONGGUAN YOUNGBO ELECTRONICS CO.,LTD

Length of cable

AE8

Model EHS61ASFWE

Manufacturer WATA ELECTRONICS CO.,LTD

Length of cable

AE9

Type HQ-50S

Manufacturer SUCD(FUJIAN) Electronics Co.,Ltd

Length of cable /

*AE ID: is used to identify the ancillary equipment in the lab internally.





3.4. EUT Set-ups

Table 1: Eut Set-ups

EUT Set-up No.	Combination of EUT and AE	Remarks
Set.NFC01	01a + AE2 + AE6 + AE9	
Set.NFC02	01a + AE9	
Set. NFC03	08a	

The Transmit State of NFC: the NFC function is on. The EUT will transmit the NFC data and command continuously during the test.

The Transmit state without modulation: The EUT will transmit the CW signal at the Hoperating frequency.





4. Reference Documents

4.1. <u>Documents supplied by applicant</u>

EUT parameters, referring to Annex A for detailed information, are supplied by the client or manufacturer, which are the bases of testing.

4.2. Reference Documents for testing

The following documents listed in this section are referred for testing.

Reference	Title	Version
CFR 47 Part 2	Part 2 — Frequency Allocations and Radio Treaty Matters; General Rules and Regulations.	2018
CFR 47 Part 15	Part 15 — Radio Frequency Devices.	2018
	Subpart C — Intentional Radiators.	
	§ 15.35 Measurement detector functions and bandwidths.	
	§ 15.207 Conducted limits.	
	§ 15.209 Radiated emission limits, general requirements.	
	§ 15.215 Additional provisions to the general radiated emission limitations.	
	§ 15.225 Operation within the band 13.110–14.010 MHz.	
ANSI C63.10	American National Standard of Procedures for Compliance	2013
	Testing of Unlicensed Wireless Devices	





5. Test Results

5.1. Summary of Test Results

Table 2: Summary of Test Results

No	Test Cases	Clause in Regulation	Section in This Report	Verdict	
1	Electric Field Strength of Fundamental Emissions	CFR 47 § 15.225(a)	D 1	P(Set. NFC02)	
2	Electric Field Strength of Outside the Allocated Bands	CFR 47 § 15.225(b) CFR 47 § 15.225(c)	B.1	P(Set. NFC02)	
3	Electric Field Radiated	CFR 47 § 15.209	B.2	P(Set. NFC01)	
	Emissions	CFR 47 § 15.225(d)	B.3	P(Set. NFC01)	
4	Frequency Tolerance	CFR 47 § 15.225(e)	B.4	P(Set. NFC03)	
5	20dB Bandwidth	CFR 47 § 15.215(c)	B.5	P(Set. NFC03)	
6	Conducted Emissions	CFR 47 § 15.207	B.6	P(Set. NFC01)	
The measurement is carried out according to ANSL C62.10. See ANNEY P for details					

The measurement is carried out according to ANSI C63.10. See **ANNEX B** for details.

Test Conditions:

For this report, all the test cases listed above were tested under normal Temperature, Voltage, humidity and Air Pressure except the Frequency Tolerance test case. The specific conditions of Frequency Tolerance test case are listed in section B.4.3

See Table 3 for terms for result verdict:

Table 3 Terms for result verdict

Р	Pass, The EUT complies with the essential requirements in the standard.
NP	Not Perform, The test was not performed by CTTL
NA	Not Applicable, The test was not applicable
F	Fail, The EUT does not comply with the essential requirements in the standard





5.2. Statements

The test cases listed in Section 5.1 of this report for the EUT specified in Section 3 were performed by CTTL according to the reference documents in Section 4.

The EUT meets all applicable requirements of the regulations and standards in Section 4.2.





6. <u>Test Facilities Utilized</u>

Table 4: Test Facilities Utilized

NO.	NAME	TYPE	SERIES NUMBER	PRODUCER	CAL. DUE DATE	CAL. INTERVAL
1.	Spectrum Analyzer	RSA3408A	B010277	Tektronix	2021-09-24	1 Year
2.	Climatic chamber	SH242	93008658	ESPEC	2021-01-18	1 Year
3.	Test Receiver	ESU26	100235	Rohde & Schwarz	2021-03-03	1 Year
4.	BiLog Antenna	VULB9163	9163-1223	Schwarzbeck	2021-03-18	1 Year
5.	LISN	ENV216	101459	R&S	2021-03-17	1 Year
6.	Test Receiver	ESCI	100766	R&S	2021-03-10	1 Year
7.	H-field Antenna	HLA-6121	40483	TES	2021-07-22	1 Year





7. Measurement Uncertainty

Table 5: Measurement Uncertainty

Item	Uncertainty
Frequency Tolerance	<i>U</i> =77 Hz, k=2
20dB Bandwidth	<i>U</i> =77 Hz, k=2
Radiated Emissions (<1GHz)	<i>U</i> =4.86 dB, k=2
Radiated Emissions (>1GHz)	<i>U</i> =5.16 dB, k=2
Conducted emission	<i>U</i> = 3.10 dB, k=2





ANNEX A: EUT parameters

/





ANNEX B: Detailed Test Results

B.1. Electric Field Strength of Fundamental and Outside the Allocated bands

B.1.1. Reference

See Clause 4, Clause 5 of ANSI C63.10-2013 generally.

B.1.2. Measurement Methods

The transmitter carrier output levels (E-Field) from the EUT are measured in a semi-anechoic chamber. The EUT is placed on a non-conductive stand of 80cm high, and at a measurement distance of 3m from the receiving antenna. The center of the receiving loop antenna is 1.0 meter above the ground. The E-field is measured with a shielded loop antenna connected to a measurement receiver. Detected E-field was maximized by rotating the EUT through 360° and adjusting the receiving antenna polarizations. The maximization processes were repeated with the EUT positioned respectively in its three orthogonal axes. The measurements were performed with the peak detector and if required, the quasi-peak detector.

The measurement bandwidth is:

Table B-1: Measurement bandwidth

Frequency of Emission (MHz)	RBW/VBW
12.56-14.56	10/30 kHz

The E-field measured at 3m is calculated as:

E-field $(dB\mu V/m) = Rx (dB\mu V) + Cable Loss (dB) + AF@3m (dB/m)$





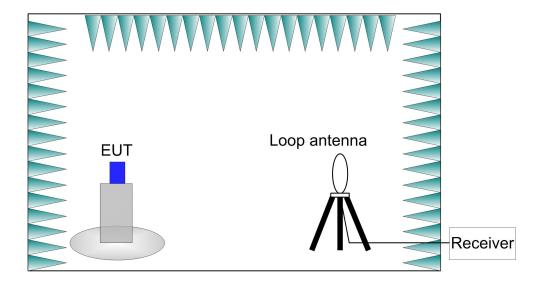


Figure B-1: Measurement Setup

B.1.3. EUT Operating Mode and Test Conditions

The measurement of EUT is carried out under the transmit state of NFC(See 3.4).

The EUT is powered by a travel adapter.

All possible configurations were investigated and only the worst case is reported.

During the measurements, the ambient temperature of the electromagnetic anechoic chamber is in the range of 15 ~ 25 $\,^{\circ}$ C.

B.1.4. Limits

Table B-2: Limits

Eroqueney Benge (MHz)	E-field Strength Limit @ 30 m	E-field Strength Limit @ 3 m
Frequency Range (MHz)	(μ V/m)	(dBµV/m)
13.560 ± 0.007	+15,848	124
13.410 to 13.553	+334	90
13.567 to 13.710		
13.110 to 13.410	+106	81
13.710 to 14.010	.00	

Note: Where the limits have been defined at one distance, and a signal level measured at another, the limits have been extrapolated using the following formula:





Extrapolation(dB) = $40\log_{10}$ (Measurement Distance/Specification Distance)

B.1.5. Measurement Results

Measurement results of normal conditions see Figure B-2 for different set-ups of EUT. The results displayed take into account applicable antenna factors and cable losses.

Conclusions: Set.NFC02, PASS.

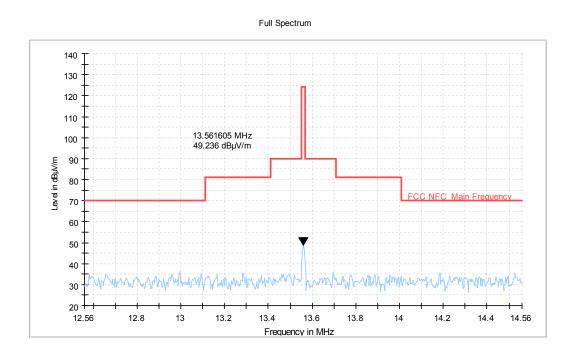


Figure B-2: Measurement results for Electric Field Strength of Fundamental and Outside the Allocated bands

B.2. Electric Field Radiated Emissions (< 30MHz)

B.2.1. Reference

See Clause 6.4 of ANSI C63.10-2013 specifically.

See Clause 4 and Clause 5 of ANSI C63.10-2013 generally.

B.2.2. Measurement Methods

The transmitter carrier output levels (E-Field) from the EUT are measured in a semi-anechoic chamber. The EUT is placed on a non-conductive stand of 80cm high, and at a measurement distance of 3m from the receiving antenna. The center of the receiving loop antenna is 1.0 meter above the ground. The E-field is measured with a shielded loop antenna connected to a





measurement receiver. Detected E-field was maximized by rotating the EUT through 360° and adjusting the receiving antenna polarizations. The maximization processes were repeated with the EUT positioned respectively in its three orthogonal axes. The measurements were performed with the peak detector and if required, the quasi-peak detector.

The measurement bandwidth is:

Table B-3: Measurement bandwidth

Frequency of Emission (MHz)	RBW/VBW
0.009-0.15	100/300 Hz
0.15-30	10/30 kHz

The E-field measured at 3m is calculated as:

E-field $(dB\mu V/m) = Rx (dB\mu V) + Cable Loss (dB) + AF@3m (dB/m)$

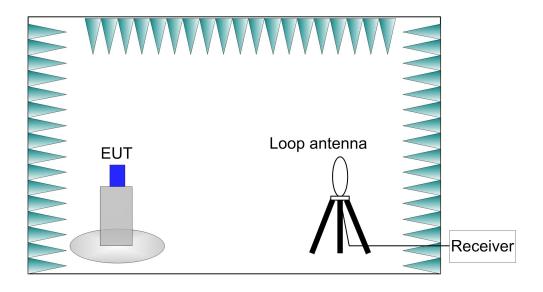


Figure B-3: Measurement Setup

B.2.3. EUT Operating Mode and Test Conditions

The measurement of EUT is carried out under the transmit state of NFC(See 3.4).

The EUT is powered by a travel adapter.

All possible configurations were investigated and only the worst case is reported.

During the measurements, the ambient temperature of the electromagnetic anechoic chamber is in the range of $15 \sim 25$ °C.





B.2.4. Limits

Table B-4: Limits

Frequency Range (MHz)	E-field Strength Limit @ 30m	E-field Strength Limit @ 3m	
r requericy range (mnz)	(mV/m)	(dBµV/m)	
0.009-0.490	2400/F(kHz)	129-94	
0.490-1.705	24000/F(kHz)	74-63	
1.705-30	30	70	

Note: Where the limits have been defined at one distance, and a signal level measured at another, the limits have been extrapolated using the following formula:

Extrapolation(dB) = $40\log_{10}$ (Measurement Distance/Specification Distance)

B.2.5. Measurement Results

Measurement results of normal conditions see Figure B-4 for different set-ups of EUT. The results displayed take into account applicable antenna factors and cable losses.

Conclusions: Set.NFC01, PASS.

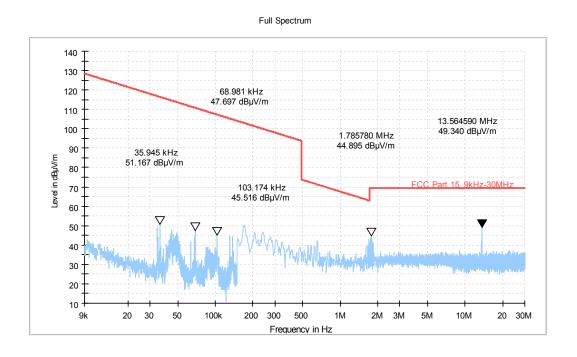


Figure B-4: Measurement results for Electric Field Radiated Emissions (< 30MHz)





B.3. Electric Field Radiated Emissions (≥30MHz)

B.3.1. Reference

See Clause 6.5 of ANSI C63.10-2013 specifically.

See Clause 4 and Clause 5 of ANSI C63.10-2013 generally.

B.3.2. Measurement Methods

The electric field radiated emissions from the EUT are measured in a semi-anechoic chamber. The EUT is placed on a non-conductive stand of 80cm high, and at a measurement distance of 10m from the receiving antenna. The receiving antennas connected to a measurement receiver. In order to search for maximum field strength emitted from the EUT, the receiving antenna can be moved between the height of 1.0 m to 4.0 m. Detected E-field was maximized at each frequency by rotating the EUT through 360° and adjusting the receiving antenna positions for both vertical and horizontal antenna polarizations. The maximization processes were repeated with the EUT positioned respectively in its three orthogonal axes. The measurements were performed with the peak detector and if required, the quasi-peak detector.

The measurement bandwidth is:

Table B-5: Measurement bandwidth

Frequency of Emission (MHz)	RBW/VBW		
30-1000	120kHz		

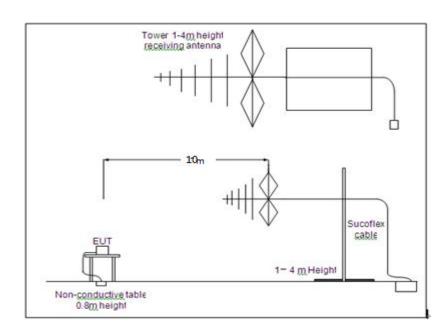


Figure B-5: Measurement Setup





B.3.3. EUT Operating Mode and Test Conditions

The measurement of EUT is carried out under the transmit state of NFC(See 3.4).

The EUT had been connected to a travel adapter.

All possible configurations were investigated and only the worst case is reported.

During the measurements, the ambient temperature of the electromagnetic anechoic chamber is in the range of $15 \sim 25$ °C.

B.3.4. Limits

Table B-6: Limits

Frequency Range (MHz)	E-field Strength Limit @ 3m (mV/m)	E-field Strength Limit @ 3m (dBµV/m)	E-field Strength Limit @ 10m (dBµV/m)
30-88	100	40	30
88-216	150	43.5	33.5
216-960	200	46	36
960-1000	500	54	44

B.3.5. Measurement Results

Measurement results of normal conditions see Figure B-6 for different set-ups of EUT. The results displayed take into account applicable antenna factors and cable losses.

Conclusions: Set.NFC01, PASS.





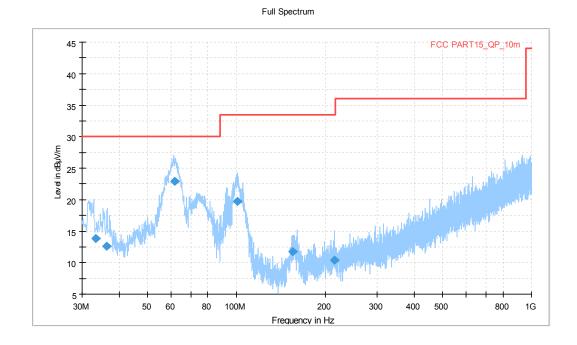


Figure B-6: Measurement results for Electric Field Radiated Emissions (≥30MHz)

Final_Result

Frequency	QuasiPeak	Height	Polarization Azimuth		Margin	Limit
(MHz)	(dBµV/m)	(cm)		(deg)	(dB)	(dBµV/m)
33.413000	13.87	178.0	V	241.0	16.13	30.00
36.319000	12.65	225.0	V	60.0	17.35	30.00
61.774000	22.92	197.0	V	13.0	7.08	30.00
100.939000	19.70	101.0	V	241.0	13.82	33.50
155.019000	11.69	104.0	V	-30.0	21.83	33.50
214.605000	10.44	101.0	V	300.0	23.08	33.50

B.4. Frequency Tolerance

B.4.1. Reference

See Clause 6.8 of ANSI C63.10-2013 specifically.

See Clause 4 and Clause 5 of ANSI C63.10-2013 generally.





B.4.2. Measurement Methods

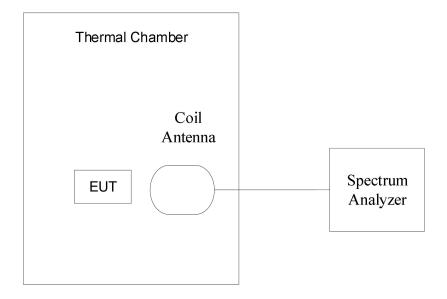


Figure B-7: Measurement Setup

The transmitter output signal was picked up by coil antenna connected to the spectrum analyzer. The center frequency was measured with 30Hz RBW and 1kHz span.

During the test, the EUT was placed in a thermal chamber until thermal balance and lasting appropriate time.

B.4.3. EUT Operating Mode and Test Conditions

The measurement of EUT was carried out under the transmit state of without modulation(See 3.4).

EUT had not been connected to a travel adapter. The frequency stability was measured with the different voltage and temperature combinations:

- a) The nominal voltage 3.85V(See 3.1)was used and the temperature was varied from -20 $^{\circ}$ C to +50 $^{\circ}$ C in 10 $^{\circ}$ C increments using an environmental chamber.
- b) The 20 $^{\circ}$ C was used and the voltages were 3.6V, 3.85V and 4.2V (The extreme low voltage ,the nominal voltage and the extreme high voltage defined in section 3.1).

The details were as following:





Table B-7: Combinations of Voltage and Temperature

Test items	Voltage	Temperature
Frequency stability with respect to ambient temperature		-20℃
		-10℃
		0℃
	3.85V	10℃
		20℃
		30℃
		40℃
		50℃
Frequency stability when varying supply	3.6V	
voltage	3.85V	20℃
	4.2V	

B.4.4. Test Layouts

See B.4.2.

B.4.5. Limits

The frequency tolerance of the carrier signal shall be maintained within +/- 0.01% of the operating frequency.

B.4.6. Measurement Results

Measurement results see Table B-9 for different test conditions.

Conclusions: Set.NFC03, PASS.





 Table B-8:
 Measurement results for Frequency Tolerance

Temperature	Voltage		Frequency (MHz)			
remperature	voltage	Startup	2 Min Later	5 Min Later	10 Min Later	
-20℃	3.85V	13.560025625	13.560029375	13.560014375	13.560010625	
-10℃	3.85V	13.560033750	13.560038125	13.560041875	13.560045625	
0℃	3.85V	13.560054375	13.560055625	13.560056250	13.560057875	
10℃	3.85V	13.560054375	13.560051875	13.560049375	13.560048125	
20℃	3.85V	13.560036875	13.560031875	13.560026875	13.560024375	
30℃	3.85V	13.560004375	13.560001875	13.559995625	13.559994375	
40°C	3.85V	13.559976875	13.559971875	13.559969375	13.559966875	
50℃	3.85V	13.559950625	13.559949375	13.559948125	13.559946875	
20℃	3.6V	13.559985625	13.560009375	13.560016875	13.560020625	
20℃	4.2 V	13.560021875	13.560022175	13.560023125	13.560024875	

Temperature	Voltage	Frequency Error (%)			
remperature	voltage	Startup	2 Min Later	5 Min Later	10 Min Later
-20℃	3.85V	0.000	0.000	0.000	0.000
-10℃	3.85V	0.000	0.000	0.000	0.000
0℃	3.85V	0.000	0.000	0.000 0.000	
10℃	3.85V	0.000	0.000	0.000 0.000	
20℃	3.85V	0.000	0.000	0.000	0.000
30℃	3.85V	0.000	0.000	0.000	0.000
40℃	3.85V	0.000	0.000	0.000	0.000
50℃	3.85V	0.000	0.000	0.000 0.000	
20℃	3.6V	0.000	0.000	0.000 0.000	
20℃	4.2V	0.000	0.000	0.000 0.000	





B.4.7. Measurement Uncertainty

Measurement uncertainty: U = 77 Hz, k=2

B.5. 20dB Bandwidth

B.5.1. Reference

See Clause 6.9 of ANSI C63.10-2013 specifically.

See Clause 4 and Clause 5 of ANSI C63.10-2013 generally.

B.5.2. Measurement Methods

The transmitter output signal was picked up by coil antenna connected to the spectrum analyzer. The bandwidth of the center frequency was measured with 140Hz RBW, 420Hz VBW and 14kHz span.

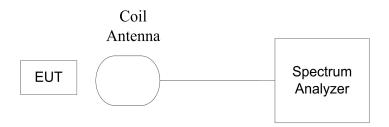


Figure B-8: Measurement Setup

B.5.3. EUT Operating Mode and Test Conditions

The measurement of EUT was carried out under the transmit state of NFC (See 3.4).

EUT had not been connected to a travel adapter.

During the measurements, the ambient temperature was in the range of $15 \sim 25$ °C.

B.5.4. Test Layouts

See B.5.2.

B.5.5. Limits

The 20dB bandwidth shall be less than 80% of the permitted frequency band. For 13.56 MHz NFC,





the permitted frequency band is 14kHz, so the limit is 11.2 kHz.

B.5.6. Measurement Results

Measurement results see Figure B-9.

Conclusions: Set.NFC03, PASS.

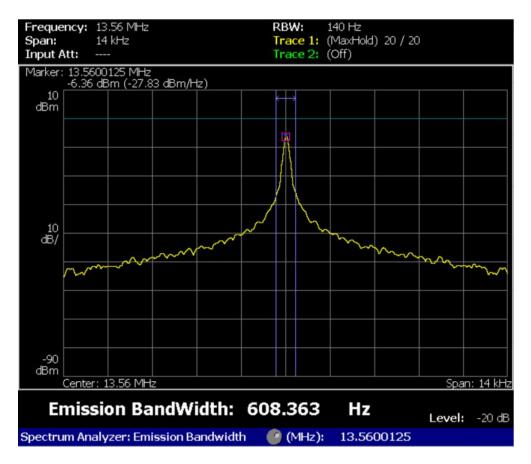


Figure B-9: Measurement results for 20dB Bandwidth

B.5.7. Measurement Uncertainty

Measurement uncertainty: *U* =77 Hz, k=2

B.6. Conducted emission

B.6.1. Reference

See Clause 6.2 of ANSI C63.10-2013 specifically.

See Clause 4 and Clause 5 of ANSI C63.10-2013 generally.

B.6.2. Measurement Methods

The conducted emissions from the AC port of the EUT are measured in a shielding room. The EUT is connected to a Line Impedance Stabilization Network (LISN). An overview sweep with peak





detection was performed. The measurements were performed with a quasi-peak detector and if required, an average detector.

The conducted emission measurements were made with the following detector of the test receiver:

Quasi-Peak / Average Detector.

The measurement bandwidth is:

Table B-9: Measurement Bandwidth

Frequency of Emission (MHz)	RBW/VBW		
0.15-30	9kHz		

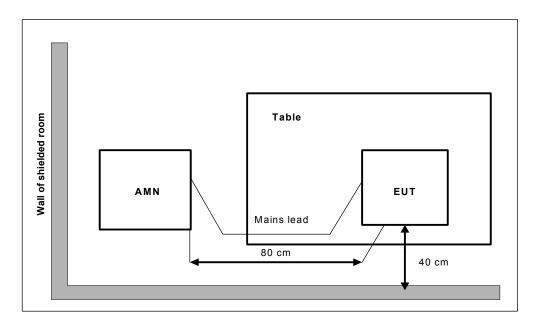


Figure B-10: Measurement Setup

B.6.3. EUT Operating Mode and Test Conditions

The measurement of EUT is carried out under the transmit state of NFC(See 3.4).

The EUT is powered by a travel adapter.

All possible configurations were investigated and only the worst case is reported.

During the measurements, the ambient temperature is in the range of 15 ~ 25 $^{\circ}$ C.

B.6.4. Limits

Table B-10: Limits

Frequency range (MHz)	Quasi-peak Limit (dBμV)	Average Limit (dBμV)
0.15 to 0.5	66 to 56	56 to 46



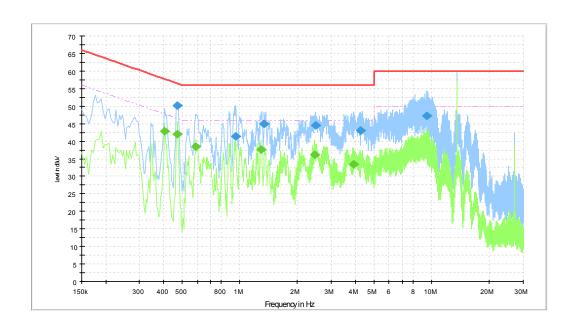


0.5 to 5	56	46
5 to 30	60	50

B.6.5. Measurement Results

Measurement results see Figure B-11.

Conclusions: Set.NFC01, PASS.



Note: the spike over the limit is the NFC carrier frequency and coming from the radio equipment.

Figure B-11: Measurement results for Conducted Emission

Final Result 1

Frequency	QuasiPeak	Meas. Time	Bandwidt	Line	Corr.	Margin	Limit
(NALI=)	/dP\/\	(ma)	h		(AD)	(AD)	(dD::\/\
0.474000	50.1	1000.0	9.000	L1	20.0	6.3	56.4
0.955500	41.3	1000.0	9.000	L1	19.9	14.7	56.0
1.342500	44.9	1000.0	9.000	L1	19.8	11.1	56.0
2.472000	44.6	1000.0	9.000	L1	19.8	11.4	56.0
4.236000	43.1	1000.0	9.000	L1	19.8	12.9	56.0
9.388500	47.1	1000.0	9.000	L1	19.9	12.9	60.0

Final Result 2

Frequency	Average	Meas. Time	Bandwidth	Line	Corr.	Margin	Limit
(MHz)	(dBµV)	(ms)	(kHz)		(dB)	(dB)	(dBµV)
0.406500	42.9	1000.0	9.000	L1	20.0	4.8	47.7
0.474000	42.0	1000.0	9.000	L1	20.0	4.5	46.4
0.591000	38.4	1000.0	9.000	L1	20.0	7.6	46.0
1.288500	37.6	1000.0	9.000	L1	19.8	8.4	46.0
2.458500	36.2	1000.0	9.000	L1	19.8	9.8	46.0
3.925500	33.4	1000.0	9.000	L1	19.8	12.6	46.0





ANNEX C: Persons involved in this testing

Table C-1: Persons involved

Test Item	Tester		
20dB Bandwidth	Zhou Bin		
Frequency Tolerance	Zhou Bin		
Electric Field Strength of Fundamental and Outside the Allocated bands	Chen Tianwei		
Electric Field Radiated Emissions (< 30MHz)	Chen Tianwei		
Electric Field Radiated Emissions (≥30MHz)	Chen Tianwei		
Conducted Emissions	Guo Qian		





ANNEX D: Accreditation Certificate

United States Department of Commerce National Institute of Standards and Technology



Certificate of Accreditation to ISO/IEC 17025:2017

NVLAP LAB CODE: 600118-0

Telecommunication Technology Labs, CAICT

Beijing China

is accredited by the National Voluntary Laboratory Accreditation Program for specific services, listed on the Scope of Accreditation, for:

Electromagnetic Compatibility & Telecommunications

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communique dated January 2009).

2020-09-29 through 2021-09-30

Effective Dates



For the National Voluntary Laboratory Accreditation Program

END OF REPORT